

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY. DOCKET NO. MI22-1533	SERIAL NO. 09/754,926	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Kie Y. Ahn et al.		
					FILING DATE January 4, 2001	GROUP 2813	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date If Appropriate
<i>SL</i>	AA	6,809,010 B1	10-2004	Kinoshita et al.	—	—	—
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub-class	Translation
	AM						Yes
	AN						No
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
EXAMINER <i>hannah Schley</i>				DATE CONSIDERED <i>7/6/06</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Sheet 1 of 1

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>AS</i>	AR	AS	Wikipedia (an online dictionary) (http://en.wikipedia.org/wiki/sapphire)

EXAMINER

DATE CONSIDERED

*Karen Schley**7/6/06*

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*Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date If Appropriate
<i>JKL</i>	AA	5,981,366	11-1999	Koyama et al.	—	—	
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FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub-class	Translation
							Yes
<i>JKL</i>	AM	58-153372	09-1983	Japan	—	—	No
	AN						
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER <i>Kie Y. Ahn</i>			DATE CONSIDERED <i>7/6/06</i>				
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<p style="text-align: right;">OCT 1 2002 U.S. PATENT AND TRADEMARK OFFICE AUG 19 2002 S88</p> <p style="text-align: center;">LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1533	SERIAL NO. 09/754,926	
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	AP							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
EK	AR		H.F. Luan et al., "High Quality T_{ox} ₂ O ₅ Gate Dielectrics with $T_{ox} < 10\text{\AA}$ " International Electron Devices Meeting, pgs. 141-144, 1999. The year of publication is sufficiently early such that the month is not in issue.					
EK	AS		O. Zywietzki et al., "Effect of Plasma Activation on the Phase Transformations of Aluminum Oxide" Surface and Coatings Technology, Vol 76/77, Iss 1/3, pgs. 754-762, 1993. The year of publication is sufficiently early such that the month is not in issue.					
EK	AT		N. Chand et al., "Tunability of Intrinsic Stress in SiO ₂ Dielectric Films Formed by Molecular Beam Deposition". Materials Research Society Symposia Proceedings, Vol 356, pgs. 195-200, 1995. The year of publication is sufficiently early such that the month is not in issue.					
EXAMINER	Eric Kuhn			DATE CONSIDERED 10/5/02				
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<p>Form PTO-149 NOV 20 2002 PATENT & TRADEMARK CENTER</p> <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1533		SERIAL NO. 09/754,926	
				APPLICANT Kie Y. Abo et al.					
				FILING DATE January 4, 2001		GROUP 2813			
U.S. PATENT DOCUMENTS									
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate	
Ex	AA	6,093,612	07/00	Suh		—	—		
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	AM							Yes	No
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	AP								
	AQ								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
Ex	AR		Wolf, S., "Silicon Processing for the VLSI Era", Vol. 2: Process Integration, 1990 Lattice Press, Sunset Beach, CA,						
			pp. 332-333.						
	AS								
	AT								
EXAMINER <i>Ex</i>			DATE CONSIDERED 2/1/03						
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